

# Circuit Note CN-0147

- J. Ž.	- 12
Circui	
10 0	
from th	ne Lab
1 00 1	74

Circuits from the Lab $^{\text{TM}}$  tested circuit designs address common design challenges and are engineered for quick and easy system integration. For more information and/or support, visit www.analoq.com/CN0147.

Devices Con	Devices Connected/Referenced		
ADF4350	Fractional-N PLL IC with Integrated VCO		
ADP150	Low Noise 3.3 V LDO		

# Powering a Fractional-N Voltage Controlled Oscillator (VCO) with Low Noise LDO Regulators for Reduced Phase Noise

## **EVALUATION AND DESIGN SUPPORT**

**Circuit Evaluation Boards** 

**ADF4350 Evaluation Board (EVAL-ADF4350-EB1Z)** 

**Design and Integration Files** 

**Schematics, Layout Files, Bill of Materials** 

#### **CIRCUIT FUNCTION AND BENEFITS**

This circuit uses low noise, low dropout (LDO) linear regulators to supply power to a wideband integrated PLL and VCO.

Wideband voltage controlled oscillators (VCOs) may have increased sensitivity to power supply noise, hence, ultralow noise regulators are recommended for best performance.

The circuit shown in Figure 1 utilizes the ADF4350, a fully integrated fractional-N PLL and VCO that can generate frequencies from 137.5 MHz to 4400 MHz. The ADF4350 is powered from the ultralow noise 3.3 V ADP150 regulator for optimal LO phase noise performance.

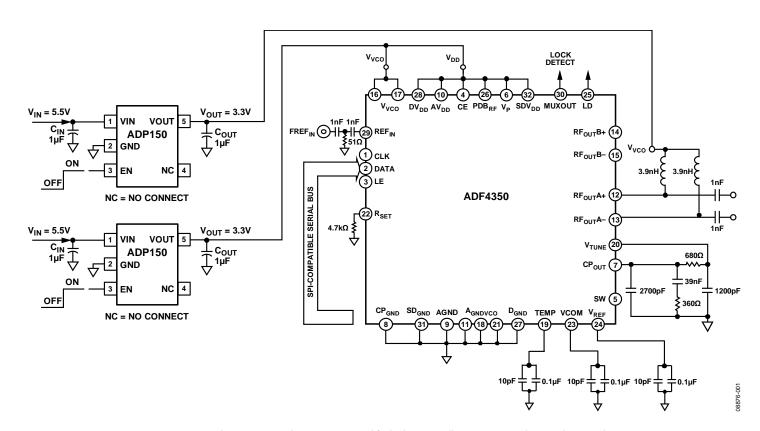


Figure 1. ADP150 Regulators Connected to ADF4350 (Simplified Schematic: All Connections and Decoupling Not Shown)

CN-0147 Circuit Note



Figure 2. EVAL-ADF4350EB1Z Rev. B Evaluation Board Featuring ADP150 Low Noise Regulators

The lower integrated rms noise of the ADP150 LDO of only 9  $\mu$ V rms (10 Hz to 100 kHz) helps to minimize VCO phase noise and reduce the impact of VCO *pushing* (the VCO equivalent of power supply rejection).

Figure 2 shows a photo of the evaluation board, which uses the ADP150 LDOs to power the ADF4350. The ADP150 represents the industry's lowest noise LDO in the smallest package at the lowest cost. It is available in a 4-ball,  $0.8~\text{mm}\times0.8~\text{mm}$ , 0.4~mm pitch WLCSP or a convenient 5-lead TSOT package. Adding the ADP150's to the design, therefore, has minimal impact on system cost and board area while providing a significant improvement in phase noise.

# **CIRCUIT DESCRIPTION**

The ADF4350 is a wideband PLL and VCO consisting of three separate multiband VCOs. Each VCO covers a range of approximately 700 MHz (with some overlap between VCOs). Lower frequencies are generated by output dividers.

VCO *pushing* is measured by applying a steady dc tuning voltage to the ADF4350  $V_{\text{TUNE}}$  pin, varying the power supply voltage, and measuring the frequency change. The pushing figure (P) equals the frequency delta divided by the voltage delta, as shown in Table 1.

In a PLL system, higher VCO pushing means that power supply noise will degrade the VCO phase noise. If VCO pushing is low, then power supply noise will not significantly degrade phase noise. However, for high VCO pushing, noisy power supplies will have a measurable impact on phase noise performance.

Table 1. ADF4350 VCO Pushing

VCO Frequency (MHz)	V <sub>TUNE</sub> (V)	VCO Pushing (MHz/V)
2200	2.5	0.73
3300	2.5	1.79
4400	2.5	5.99

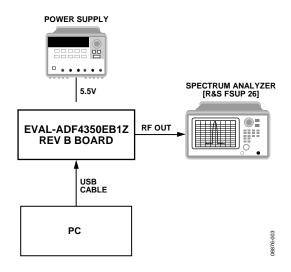


Figure 3. ADF4350 Measurement Setup

Experiments showed pushing to be at its maximum at 4.4 GHz VCO output frequency, so the comparison of VCO performance with different regulators was made at this frequency. Rev. A evaluation boards of the ADF4350 used the ADP3334 LDO regulator. The integrated rms noise of this regulator is 27  $\mu V$  (integrated from 10 Hz to 100 kHz). This compares to 9  $\mu V$  for the ADP150, which is used on the EVAL-ADF4350EB1Z, Rev B. In order to measure the impact of the power supply noise, a narrow PLL loop bandwidth (10 kHz) was used to facilitate greater examination of VCO phase noise. A diagram of this setup is shown in Figure 3. A more detailed examination of the output noise density with frequency is available from the data sheets of both the ADP3334 and ADP150.

Figure 4 shows that the noise spectral density of the ADP3334 regulator is 150 nV/ $\sqrt{\text{Hz}}$  at 100 kHz offset. The same plot for the ADP150 (Figure 5) shows 25 nV/ $\sqrt{\text{Hz}}$ .

The formula for calculating the degradation in phase noise due to the power supply noise is as follows:

$$L_{(LDO)} = 20 \log \left( \frac{P \times Sfm}{\sqrt{2} \times fm} \right)$$

Where  $L_{(LDO)}$  is the noise contribution from the regulator to the VCO phase noise (in dBc/Hz), at an offset fm; P is the VCO pushing figure in Hz/V; Sfm is the noise spectral density at a given frequency offset in V/ $\sqrt{\text{Hz}}$ ; and fm is the frequency offset at which the noise spectral density is measured in Hz.

Circuit Note CN-0147

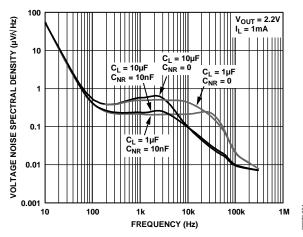


Figure 4. ADP3334 Output Noise Spectrum

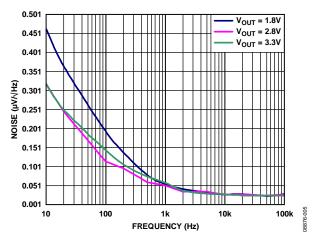


Figure 5. ADP150 output noise spectrum

The noise contribution from the supply is then rss summed with the noise contribution of the VCO (itself measured with a very low noise supply) to give the total noise at the VCO output with a given regulator.

These noise performances are rss summed together to give the expected VCO phase noise:

$$L_{(TOTAL)} = \sqrt{{L_{(VCO)}}^2 + {L_{(LDO)}}^2}$$

Or expressed in dB

$$L_{(TOTAL)} = 10 \log \left[ \left( 10^{LVCO/20} \right)^2 + \left( 10^{LLDO/20} \right)^2 \right]$$

In this example, a 100 kHz noise spectral density offset is chosen, a 6 MHz/V pushing figure is used, and -110 dBc/Hz is taken as the VCO noise with an ideal supply.

Using a dedicated signal source analyzer (like Rohde & Schwarz FSUP), the VCO phase noise is compared. At 100 kHz offset the ADP3334 delivers –102.6 dBc/Hz (Figure 6), and in the same configuration the ADP150 measures –108.5 dBc/Hz (Figure 7).

Table 2. Calculation and Measurement of VCO Noise

	ADP3334	ADP150
Noise contribution from regulator		
(nV/√Hz)	150	25
Noise contribution from regulator		
(dBc/Hz)	-104	-119.5
Total calculated noise at VCO output		
(dBc/Hz)	-103	-109.5
Measured VCO noise at 100 kHz offset		
(dBc/Hz)	-102.6	-108.5

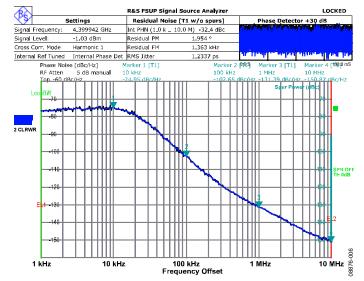


Figure 6. ADF4350 Phase Noise at 4.4 GHz with ADP3334 Regulators

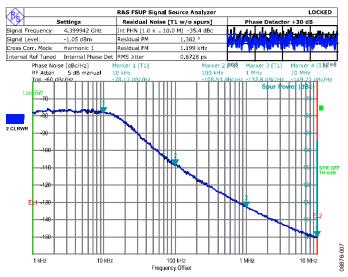


Figure 7. ADF4350 Phase Noise at 4.4 GHz with ADP150 Regulators

The integrated phase noise improves from 1.95° to 1.4° rms also. The measured results correlate very closely with the calculations and clearly show the benefit of using the ADP150 with the ADF4350.

A complete design support package for this circuit note can be found at http://www.analog.com/CN0147-DesignSupport.

CN-0147 Circuit Note

#### **COMMON VARIATIONS**

Additional regulators can be added for greater isolation between power supplies, if desired. Also, one ADP150 regulator can be used to power the entire ADF4350 part. However, care needs to be taken in this case to ensure the maximum rated current of the single ADP150 regulator is not exceeded. This is possible if the lowest output power setting on the ADF4350 is selected.

#### **CIRCUIT EVALUATION AND TEST**

This circuit note, CN-0147, uses the EVAL-ADF4350EB1Z board for evaluation of the described circuit, allowing for quick setup and evaluation. The EVAL-ADF4350EB1Z board uses the standard ADF4350 programming software, contained on the CD that accompanies the evaluation board.

# **Equipment Needed**

Windows® XP, Windows, Vista (32-bit), or Windows 7 (32-bit) PC with USB Port, the EVAL-ADF4350EB1Z, the ADF4350 programming software, 5.5 V power supply, and a spectrum analyzer such as a Rhode and Schwartz FSUP26. See this circuit note CN-0147 and UG-109 user guide for evaluation board EVAL-ADF4350EB1Z and the ADF4350 data sheet.

# **Getting Started**

This circuit note, CN-0147, contains a description of the circuit, the schematic, and a block diagram of the test setup. The ser guide, UG-109, details the installation and use of the EVAL-ADF4350 evaluation software. UG-109 also contains board setup instructions and the board schematic, layout, and bill of materials.

# **Functional Block Diagram**

This circuit note, CN-0147, contains the function block diagram of the described test setup in Figure 3.

#### Setup and Test

After setting up the equipment, standard RF test methods should be used to measure the spectral purity of the output signal.

#### **LEARN MORE**

CN0147 Design Support Package: http://www.analog.com/CN0147-DesignSupport

ADIsimPLL Design Tool

ADIsimPower Design Tool

Basso, C., C. Fourtet, and P. Kadanka. "Get the Best from Your Low-Dropout Regulator." *EDN*, 18 Feb. 1999.

## **Data Sheets and Evaluation Boards**

ADF4350 Data Sheet

ADF4350 Evaluation Board

ADP150 Data Sheet

ADP3334 Data Sheet

#### **REVISION HISTORY**

6/11—Rev. B to Rev. C

4/10—Revision 0: Initial Version

(Continued from first page) Circuits from the Lab circuits are intended only for use with Analog Devices products and are the intellectual property of Analog Devices or its licensors. While you may use the Circuits from the Lab circuits in the design of your product, no other license is granted by implication or otherwise under any patents or other intellectual property by application or use of the Circuits from the Lab circuits. Information furnished by Analog Devices is believed to be accurate and reliable. However, Circuits from the Lab circuits are supplied "as is" and without warranties of any kind, express, implied, or statutory including, but not limited to, any implied warranty of merchantability, noninfringement or fitness for a particular purpose and no responsibility is assumed by Analog Devices for their use, nor for any infringements of patents or other rights of third parties that may result from their use. Analog Devices reserves the right to change any Circuits from the Lab circuits at any time without notice but is under no obligation to do so.

